



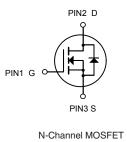
# Product data sheet

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TO-252

### **Absolute Maximum Ratings**

#### Description

The AOD478-MS is the highest performance trench N-ch MOSFETs with extreme high cell density, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The AOD478-MS meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

#### **Product Summary**

BVDSS	RDSON	ID
100V	70 mΩ	20A

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	100	V
V <sub>GS</sub>	Gate-Source Voltage	±20	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	20	А
I₀@Tc=100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	10	А
I₀@T <sub>A</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	5	А
I <sub>D</sub> @T <sub>A</sub> =70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	3.4	A
Ідм	Pulsed Drain Current <sup>2</sup>	30	А
EAS	Single Pulse Avalanche Energy <sup>3</sup>	6.1	mJ
las	Avalanche Current	15	А
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>3</sup>	34.7	W
P <sub>D</sub> @T <sub>A</sub> =25°C	Total Power Dissipation <sup>3</sup>	2	W
Tstg	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

### **Thermal Data**

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction-ambient <sup>1</sup>		62	°C/W
Rejc	Thermal Resistance Junction-Case <sup>1</sup>		3.6	°C/W



## Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	100			V
$\triangle BV_{\text{DSS}} / \triangle T_{\text{J}}$	BVDSS Temperature Coefficient	Reference to $25^{\circ}C$ , $I_D=1mA$		0.098		V/°C
<b>D</b>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =10A		70	87	mΩ
R <sub>DS(ON)</sub>		V <sub>GS</sub> =4.5V , I <sub>D</sub> =8A		85	90	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage		1.0		2.5	V
$ riangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	──V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA		-4.57		mV/°C
	Dursin Source Lookene Current	V <sub>DS</sub> =80V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =80V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	uA
Igss	Gate-Source Leakage Current	$V_{GS}=\pm 20V$ , $V_{DS}=0V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =10A		13		S
Rg	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		2		Ω
Qg	Total Gate Charge (10V)			26.2		
$Q_{gs}$	Gate-Source Charge			4.6		nC
Q <sub>gd</sub>	Gate-Drain Charge			5.1		
T <sub>d(on)</sub>	Turn-On Delay Time			4.2		
Tr	Rise Time	$V_{DD}$ =50V , $V_{GS}$ =10V , $R_{G}$ =3.3 $\Omega$		8.2		
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =10A		35.6		ns
T <sub>f</sub>	Fall Time			9.6		
Ciss	Input Capacitance			1535		
Coss	Output Capacitance Vbs=15V , Vgs=0V , f=1MHz			60		pF
Crss	Reverse Transfer Capacitance			37		

#### **Diode Characteristics**

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
ls	Continuous Source Current <sup>1,5</sup>				20	А
Ism	Pulsed Source Current <sup>2,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			30	А
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1.2	V
t <sub>rr</sub>	Reverse Recovery Time			37		nS
Qrr	Reverse Recovery Charge	IF=10A,dI/dt=100A/µs,TJ=25°C		27.3		nC

Note :

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width  $\,\leq\,$  300us , duty cycle  $\,\leq\,$  2%

3. The EAS data shows Max. rating . The test condition is  $V_{DD}$ =25V, $V_{GS}$ =10V,L=0.1mH,I<sub>AS</sub>=11A

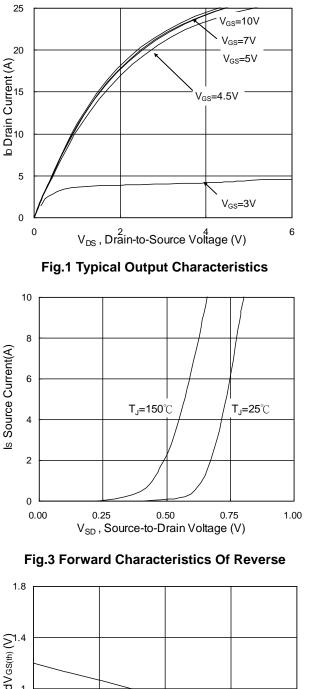
4.The power dissipation is limited by 150  $^\circ\text{C}$  junction temperature

5. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.





# **Typical Characteristics**



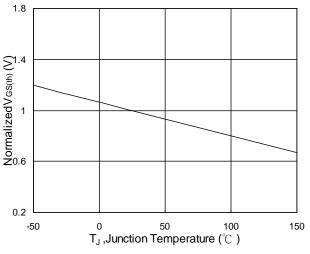


Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$ 

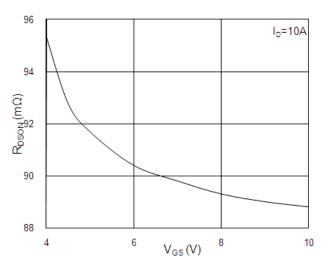


Fig.2 On-Resistance vs. Gate-Source

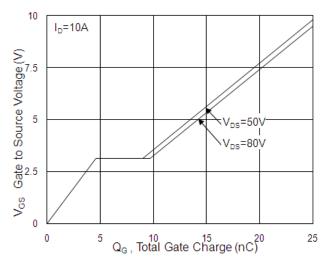


Fig.4 Gate-Charge Characteristics

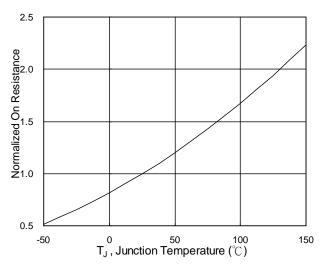
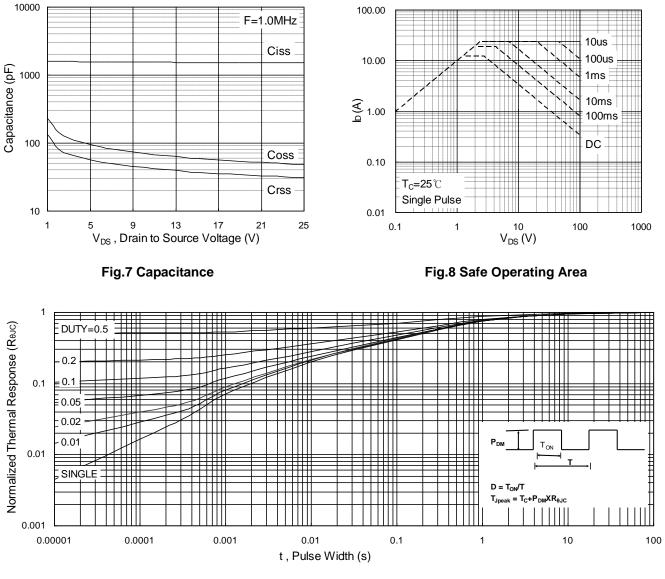


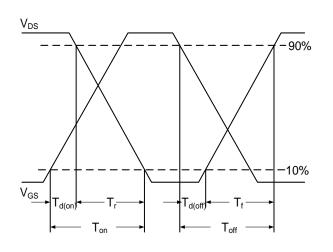
Fig.6 Normalized RDSON vs. TJ













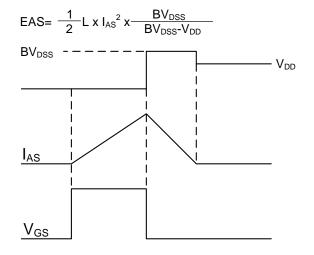
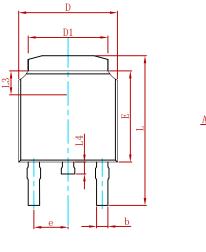


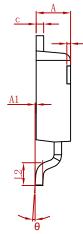
Fig.11 Unclamped Inductive Switching Waveform



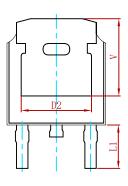


# PACKAGE MECHANICAL DATA



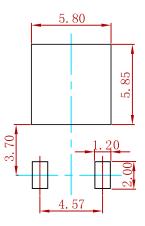


h



Symbol	Dimensions	In Millimeters	Dimension	s In Inches
Symbol	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.635	0.770	0.025	0.030
С	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830	REF.	0.190	REF.
E	6.000	6.200	0.236	0.244
е	2.186	2.386	0.086	0.094
L	9.712	10.312	0.382	0.406
L1	2.900	REF.	0.114 REF.	
L2	1.400	1.700	0.055	0.067
L3	1.600	REF.	REF. 0.063 REF.	
L4	0.600	1.000	0.024	0.039
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.250	REF.	0.207	REF.

# Suggested Pad Layout



Note:

1.Controlling dimension:in millimeters.

2.General tolerance:± 0.05mm.

3. The pad layout is for reference purposes only.

## **REEL SPECIFICATION**

P/N	PKG	QTY
AOD478-MS	TO-252	2500



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